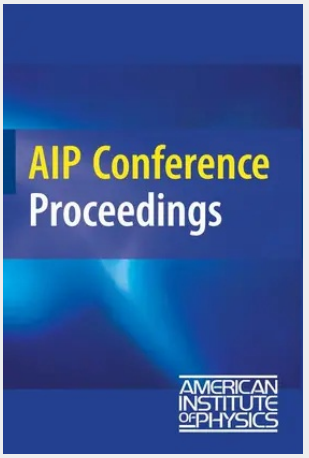
Denecke / Walker

X-Ray Optics and Microanalysis

Proceedings of the 20th International Congress

ICXOM Series is a platform dedicated for reporting progress in fundamental and applied research in x-ray optics and micro- and nano-analysis by means of x-ray beams (with an ICXOM20 emphasis on synchrotron sources), electrons or other energetic particles, including application examples, as well as methodological and instrumental developments.



112,30 €
104,95 € (zzgl. MwSt.)

Nicht mehr lieferbar

Artikelnummer: 9780735407640
Medium: Buch
ISBN: 978-0-7354-0764-0
Verlag: AIP Press
Erscheinungstermin: 04.06.2010
Sprache(n): Englisch
Auflage: 1. Auflage 2010
Serie: AIP Conference Proceedings / Atomic, Molecular, Chemical Physics
Produktform: Gebunden
Seiten: 228

Kundenservice Verlag Dr. Otto Schmidt KG
Neumannstraße 10, 40235 Düsseldorf | kundenservice@otto-schmidt.de | 0221-93738-997 (Inland)